













ESD

TVS

TSS

MOV

GDT

# TPD4E05U06DQAR-MS

**Product specification** 





#### Features

- Solid-state silicon-avalanche technology
- Lowoperating and clamping voltage
- Up to four I/OLines of Protection
- Ultra low capacitance: 0.5pFtypical(I/O to I/O)
- Low Leakage
- Low operating voltage:3.3V
- Flow-Through design

#### **IEC COMPATIBILITY (EN61000-4)**

- IEC 61000-4-2 (ESD) ±15kV (air), ±8kV (contact)
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5(Lightning) 5A(8/20μs)

### **Mechanical Characteristics**

- USON-10 package (2.5×1.0×0.58mm)
- Molding compound flammability rating: UL 94V-0
- Packaging: Tape and Reel
- RoHS/WEEE Compliant

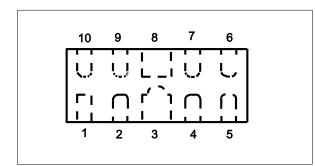
#### Applications

- Digital Visual Interface(DVI)
- MDDI Ports
- DisplayPortTM Interface
- PCI Express
- High Definition Multi-Media Interface(HDMI)
- eSATA Interfaces

#### **Reference News**

PACKAGE OUTLINE	Circuit Diagram	Marking
	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	117VH •
USON-10		

#### Schematic & PIN Configuration



Pin	Identificaion
1,2,4,5	Input Lines
6,7,9, 10	Output Lines (No Internal Connection)
3,8	Ground

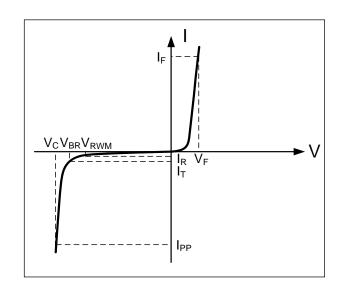


### Absolute Maximum Rating

Rating	Symbol	Value	Units
Peak Pulse Power ( $t_p = 8/20 \mu s$ )	Ppp	80	Watts
Peak Pulse Current ( $t_p = 8/20 \mu s$ )	I <sub>pp</sub>	5	А
ESD per IEC 61000-4-2(Air) ESD per IEC 61000-4-2(contact)	Vesd	+/-25 +/-25	kV
Operating Temperature	TJ	-55 to + 125	°C
Storage Temperature	T <sub>STG</sub>	-55 to +150	°C

## **Electrical Parameters (T=25°C)**

Symbol	Parameter		
PP	Maximum Reverse Peak Pulse Current		
Vc	Clamping Voltage @ IPP		
Vrwm	Working Peak Reverse Voltage		
IR	Maximum Reverse Leakage Current @ VRWM		
VBR	Breakdown Voltage @ I⊤		
Ь	Test Current		
F	Forward Current		
VF	Forward Voltage @ IF		



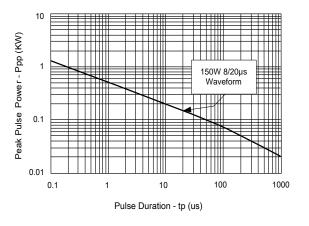
### **Electrical Characteristics**

Parameter	Symbol	Conditions	Minimum	Typical	Maximum	Units
Reverse Stand-Off Voltage	V <sub>RWM</sub>	Any I/O pin to ground			3.3	V
Reverse Breakdown Voltage	V <sub>BR</sub>	l₁ = 1mA Any I/O pin to ground	6.0			V
Reverse Leakage Current	I <sub>R</sub>	$V_{RWM}$ = 3V, T=25°C Any I/O pin to ground			1	μA
Clamping Voltage	Vc	I <sub>pp</sub> =5A, t <sub>p</sub> =8/20 μ s Any I/O pin to ground			15	V
Junction Capacitance	Cj	V <sub>R</sub> = 0V, f = 1MHz I/O pin to GND			0.8	pF
		$V_R = 0V$ , f = 1MHz Between I/O pins		0.3		pF

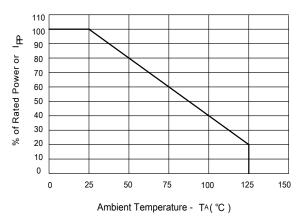


### **Typical Characteristics**

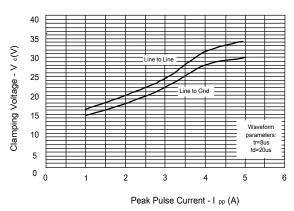
#### Non-Repetitive Peak Pulse Power vs. Pulse Time

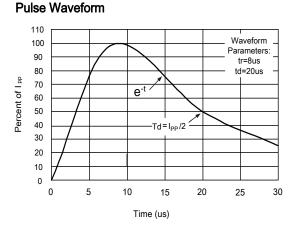


Power Derating curve

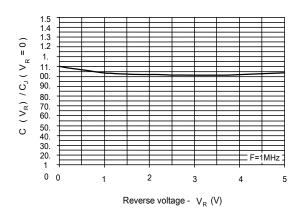


Clamping Voltage vs.Peak Pulse Current

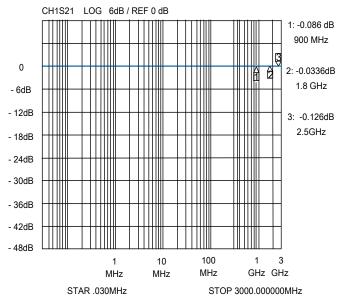








Insertion Loss S21 - I/O to GND



#### **Design Recommendations for HDMI protection**

Adding external ESD protection to HDMI ports can be challenging. First, ESD protection devices have an inherent junction capacitance. Furthermore, adding even a small amount of capacitance will cause the impedance of the differential pair to drop. Second, large packages and land pattern requirements cause discontinuities that adversely affect signal integrity. The TPD4E05U06DQAR-MS are specifically designed for protection of high-speed interfaces such as HDMI.

They present <0.4pF capacitance between the pairs while being rated to handle ±25kV ESDcontact discharges (±25kV air discharge) as outlined in IEC 61000-4-2. Each device is in a leadless SLP package that is less than 1.1mm wide. They are designed such that the traces flow straight through the device. The narrow package and flow-through design reduces discontinuities and minimizes impact on signal integrity. This becomes even more critical as signal speeds increase.

#### **Pin Configuration**

Figure 1 is an example of how to route the high speed differential traces through the ESD3V3U4ULC . The solid line represents the PCB trace. The PCB traces are used to connect the pin pairs for each line (pin 1 to pin 10, pin 2 to pin 9, pin 4 to pin 7, pin 5 to pin 6). For example, line 1 enters at pin 1 and exits at Pin 10 and the PCB trace connects pin 1 and 10 together. This is true for lines connected at pins 2, 4, and 5 also. Ground is connected at pins 3 and 8. One large ground pad should be used in lieu of two separate pads. The same layout rules apply for the ESD3V3U4ULC.

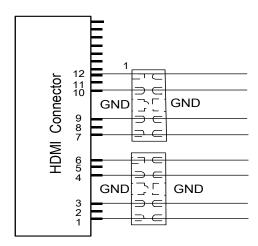


Figure 1.Flow though layout Using

#### **Design Recommendations for HDMI Protection**

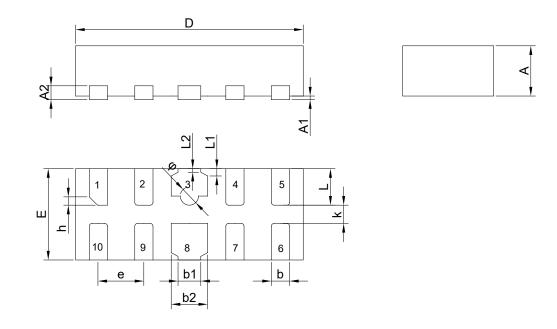
Good circuit board layout is critical not only for signal integrity, but also for effective suppression of ESD induced transients. For optimum ESD protection, the following guidelines are recommended:

- Place the device as close to the connector as possible. This practice restricts ESD coupling into adjacent traces and reduces parasitic inductance.
- The ESD transient return path to ground should be kept as short as possible.
  Whenever possible, use multiple micro vias connected directly from the device ground pad to the ground plane.
- Avoid running critical signals near board edges.



# TPD4E05U06DQAR-MS

## Dimension (DFN2510)



	Dimensions in Millimeter						
Symbol	Min.	Nom.	Max.	Symbol	Min.	Nom.	Max.
A	0.500	0.550	0.600	D	2.450	2.500	2.550
A1	0.00	/	0.05	E	0.950	1.00	1.050
A2	0.122	0.152	0.200	е	0.450	0.500	0.550
b	0.150	0.200	0.250	h	0.080	0.120	0.150
b1	0.200	0.250	0.300	k	0.150	0.200	0.250
b2	0.350	0.400	0.450	L	0.350	0.400	0.450
L1	0.075 REF		L2	0.05 REF			
φ	0.150	0.200	0.250				

#### **REEL SPECIFICATION**

P/N	PKG	QTY
TPD4E05U06DQAR-MS	DFN2510	3000



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